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| Notice of References Cited | Application/Control No. 10/673,040 | Applicant(s)/Patent Under Reexamination THESS ET AL. | |
| | Examiner Neveen Abel-Jalil | Art Unit 2165 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-6,006,223 | 12-1999 | Agrawal et al. | 707/5 |
| * | B | US-6,308,172 | 10-2001 | Agrawal et al. | 707/5 |
| * | C | US-6,996,551 | 02-2006 | Hellerstein et al. | 706/48 |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|--|
| | U | Jay Ayres, Johannes Gehrke, Tomi Yiu, and Jason Flannick. Sequential Pattern Mining using A bitmap Representation. Dept. of Computer Science, Cornell University. July 2002. |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.